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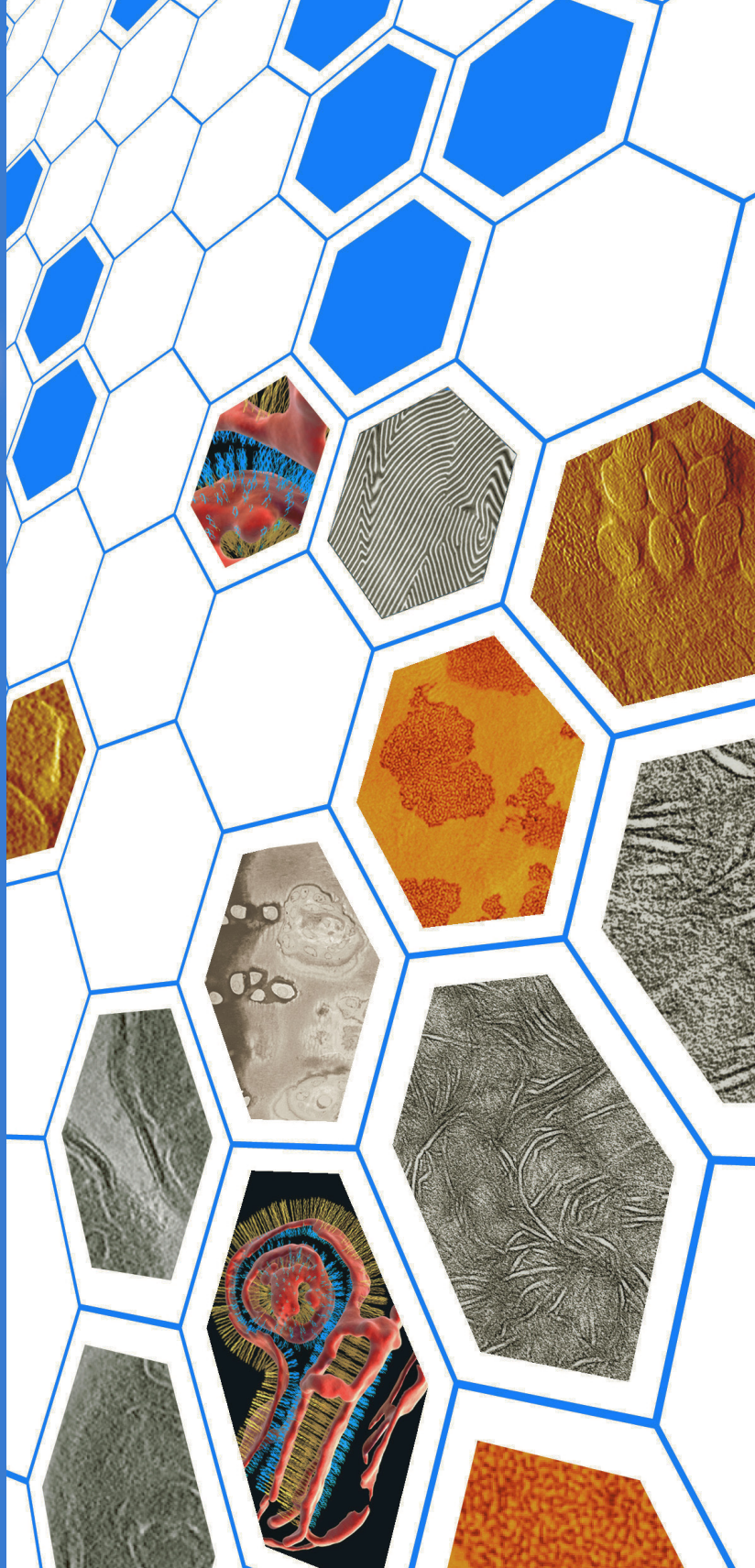
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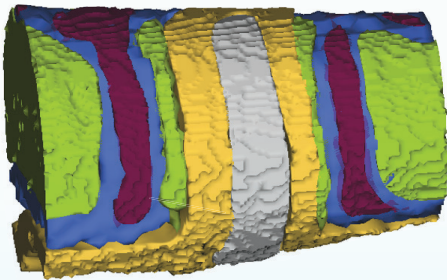
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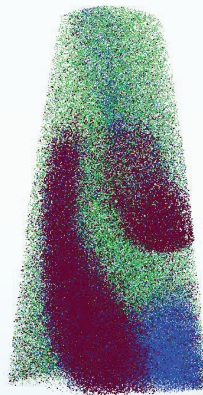
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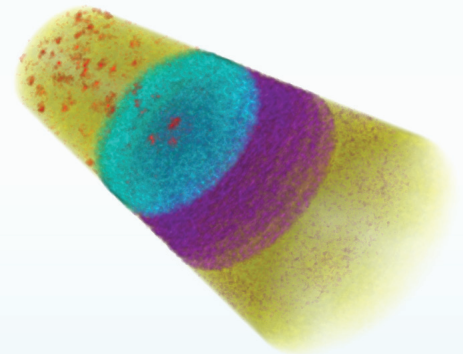
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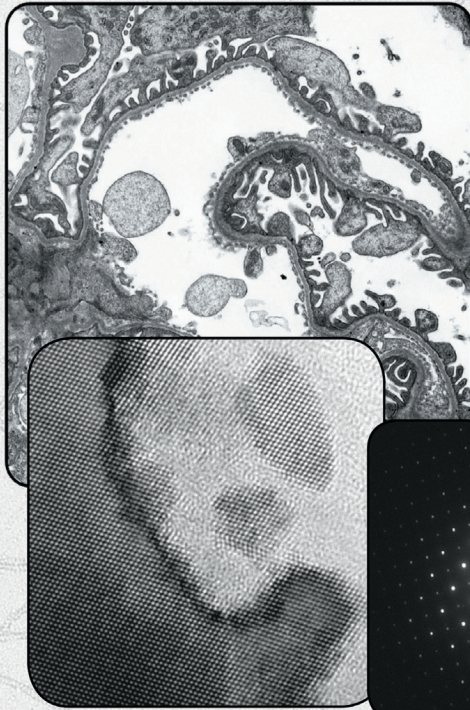
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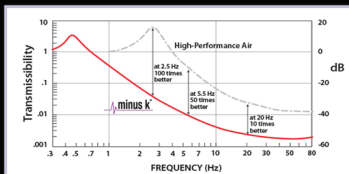
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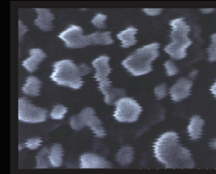
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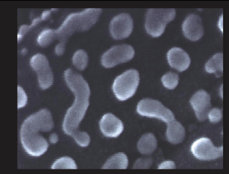
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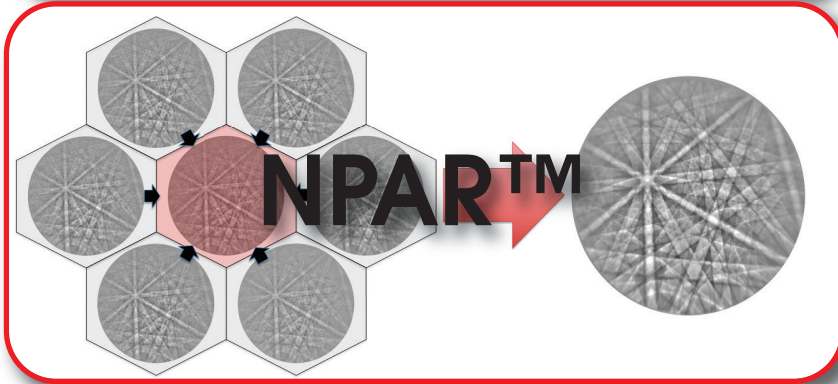
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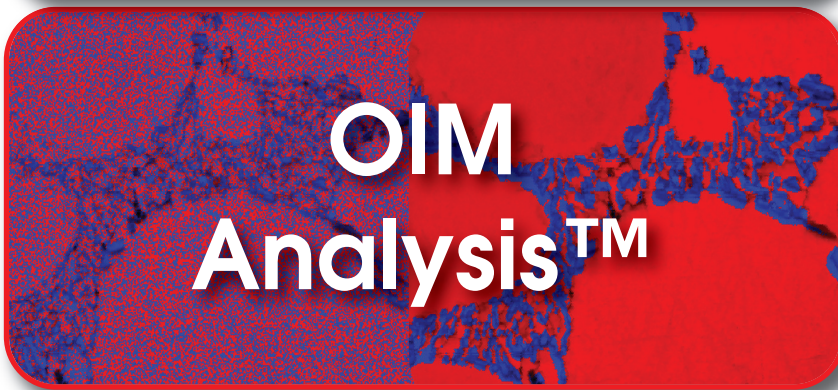
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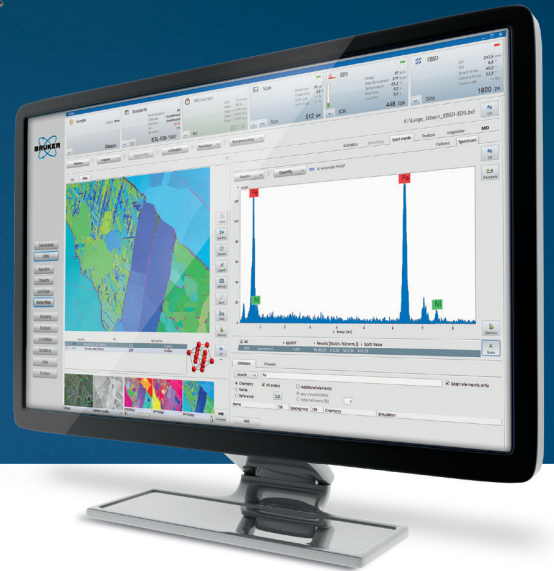
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# QUANTAX EBSD - Featuring OPTIMUS™ TKD, ARGUS™, ESPRIT QUBE and PicoIndenter®



## Unique Solutions for EBSD and TKD



- Fastest simultaneous EBSD/EDS analysis
- OPTIMUS™ - EBSD and TKD with one detector
- Unique ARGUS™ FSE/BSE imaging system
- ESPRIT QUBE for advanced 3D analysis of EBSD/EDS data
- **NEW** Quantitative in-situ nanomechanical testing with Hysitron SEM PicoIndenter®



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Innovation with Integrity

EBSD